

**Search Notes**

Application/Control No.

10/509,381

Examiner

Khanh V. Nguyen

Applicant(s)/Patent under  
Reexamination

JARNO ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	43	2/27/2006	NKV
	44		
	45		
315	3		
	3.5		
	3.6		
	5.38		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR